

Notice of References Cited	Application/Control No. 10/519,216	Applicant(s)/Patent Under Reexamination WANG ET AL.	
	Examiner CHIH-MIN KAM	Art Unit 1656	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Iyer et al. , Abstracts of Papers, 221st ACS national meeting, San Diego, CA, United States, April 1-5, 2001, ANYL-035.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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